

MC74AC132, MC74ACT132

Quad 2-Input NAND Schmitt Trigger

The MC74AC/74ACT132 contains four 2-input NAND gates which are capable of transforming slowly changing input signals into sharply defined, jitter-free output signals. In addition, they have greater noise margin than conventional NAND gates.

Each circuit contains a 2-input Schmitt trigger. The Schmitt trigger uses positive feedback to effectively speed-up slow input transitions, and provide different input threshold voltages for positive and negative-going transitions. This hysteresis between the positive-going and negative-going input threshold is determined by resistor ratios and is essentially insensitive to temperature and supply voltage variations.

Features

- Schmitt Trigger Inputs
- Outputs Source/Sink 24 mA
- 'ACT132 Has TTL Compatible Inputs
- Pb-Free Packages are Available

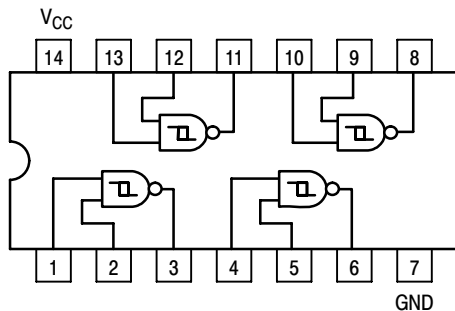


Figure 1. Pinout; 14-Lead Packages Conductors (Top View)

FUNCTION TABLE

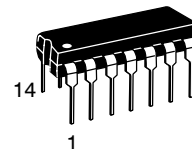
Inputs		Output
A	B	\bar{Y}
L	L	H
L	H	H
H	L	H
H	H	L

H = HIGH Voltage Level L = LOW Voltage Level

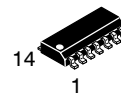


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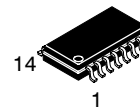
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PDIP-14
N SUFFIX
CASE 646



SOIC-14
D SUFFIX
CASE 751A



SOEIAJ-14
M SUFFIX
CASE 965

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

MC74AC132, MC74ACT132

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Typ	Max	Unit	
V _{CC}	Supply Voltage	'AC	2.0	5.0	6.0	V
		'ACT	4.5	5.0	5.5	
V _{in} , V _{out}	DC Input Voltage, Output Voltage (Ref. to GND)	0	–	V _{CC}	V	
t _r , t _f	Input Rise and Fall Time (Note 1) 'AC Devices except Schmitt Inputs	V _{CC} @ 3.0 V	–	150	–	ns/V
		V _{CC} @ 4.5 V	–	40	–	
		V _{CC} @ 5.5 V	–	25	–	
t _r , t _f	Input Rise and Fall Time (Note 2) 'ACT Devices except Schmitt Inputs	V _{CC} @ 4.5 V	–	10	–	ns/V
		V _{CC} @ 5.5 V	–	8.0	–	
T _J	Junction Temperature (PDIP)	–	–	140	°C	
T _A	Operating Ambient Temperature Range	–40	25	85	°C	
I _{OH}	Output Current – High	–	–	–24	mA	
I _{OL}	Output Current – Low	–	–	24	mA	

1. V_{in} from 30% to 70% V_{CC}; see individual Data Sheets for devices that differ from the typical input rise and fall times.
2. V_{in} from 0.8 V to 2.0 V; see individual Data Sheets for devices that differ from the typical input rise and fall times.

DC CHARACTERISTICS

Symbol	Parameter	V _{CC} (V)	74AC		74ACT		Unit	Conditions
			T _A = +25°C		T _A = –40°C to +85°C			
			Typ	Guaranteed Limits				
V _{OH}	Minimum High Level Output Voltage	3.0	2.99	2.9	2.9	V	I _{OUT} = –50 μA	
		4.5	4.49	4.4	4.4			
		5.5	5.49	5.4	5.4			
		3.0	–	2.56	2.46	V	*V _{IN} = V _{IL} or V _{IH} –12 mA I _{OH} –24 mA –24 mA	
		4.5	–	3.86	3.76			
		5.5	–	4.86	4.76			
V _{OL}	Maximum Low Level Output Voltage	3.0	0.002	0.1	0.1	V	I _{OUT} = 50 μA	
		4.5	0.001	0.1	0.1			
		5.5	0.001	0.1	0.1			
		3.0	–	0.36	0.44	V	*V _{IN} = V _{IL} or V _{IH} 12 mA I _{OL} 24 mA 24 mA	
		4.5	–	0.36	0.44			
		5.5	–	0.36	0.44			
I _{IN}	Maximum Input Leakage Current	5.5	–	±0.1	±1.0	μA	V _I = V _{CC} , GND	
I _{OLD}	†Minimum Dynamic Output Current	5.5	–	–	75	mA	V _{OLD} = 1.65 V Max	
I _{OHD}		5.5	–	–	–75	mA	V _{OHD} = 3.85 V Min	
I _{CC}	Maximum Quiescent Supply Current	5.5	–	4.0	40	μA	V _{IN} = V _{CC} or GND	

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

NOTE: I_{IN} and I_{CC} @ 3.0 V are guaranteed to be less than or equal to the respective limit @ 5.5 V V_{CC}.

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AC CHARACTERISTICS (For Figures and Waveforms – See Section 3 of the ON Semiconductor FACT Data Book, DL138/D)

Symbol	Parameter	V _{CC} * (V)	74AC			74AC		Unit	Fig. No.
			T _A = +25°C C _L = 50 pF			T _A = -40°C to +85°C C _L = 50 pF			
			Min	Typ	Max	Min	Max		
t _{PLH}	Propagation Delay	3.3 5.0	2.0 2.0	– –	13.0 9.0	1.5 1.5	14.0 10.0	ns	3–5
t _{PHL}	Propagation Delay	3.3 5.0	2.0 2.0	– –	13.5 9.0	1.5 1.5	15.0 10.0	ns	3–5

*Voltage Range 3.3 V is 3.3 V ±0.3 V.
Voltage Range 5.0 V is 5.0 V ±0.5 V.

DC CHARACTERISTICS

Symbol	Parameter	V _{CC} (V)	74ACT		74ACT		Unit	Conditions
			T _A = +25°C		T _A = -40°C to +85°C			
			Typ	Guaranteed Limits				
V _{OH}	Minimum High Level Output Voltage	4.5	4.49	4.4	4.4	V	I _{OUT} = -50 μA	
		5.5	5.49	5.4	5.4			
V _{OL}	Maximum Low Level Output Voltage	4.5	–	3.86	3.76	V	*V _{IN} = V _{IL} or V _{IH} -24 mA I _{OH} -24 mA	
		5.5	–	4.86	4.76			
V _{OL}	Maximum Low Level Output Voltage	4.5	0.001	0.1	0.1	V	I _{OUT} = 50 μA	
		5.5	0.001	0.1	0.1			
V _{OL}	Maximum Low Level Output Voltage	4.5	–	0.36	0.44	V	*V _{IN} = V _{IL} or V _{IH} 24 mA I _{OL} 24 mA	
		5.5	–	0.36	0.44			
I _{IN}	Maximum Input Leakage Current	5.5	–	±0.1	±1.0	μA	V _I = V _{CC} , GND	
ΔI _{CC} T	Additional Max. I _{CC} /Input	5.5	0.6	–	1.5	mA	V _I = V _{CC} - 2.1 V	
I _{OLD}	†Minimum Dynamic Output Current	5.5	–	–	75	mA	V _{OLD} = 1.65 V Max	
I _{OHD}		5.5	–	–	-75	mA	V _{OHD} = 3.85 V Min	
I _{CC}	Maximum Quiescent Supply Current	5.5	–	4.0	40	μA	V _{IN} = V _{CC} or GND	

*All outputs loaded; thresholds on input associated with output under test.
†Maximum test duration 2.0 ms, one output loaded at a time.

AC CHARACTERISTICS (For Figures and Waveforms – See Section 3 of the ON Semiconductor FACT Data Book, DL138/D)

Symbol	Parameter	V _{CC} * (V)	74ACT			74ACT		Unit	Fig. No.
			T _A = +25°C C _L = 50 pF			T _A = -40°C to +85°C C _L = 50 pF			
			Min	Typ	Max	Min	Max		
t _{PLH}	Propagation Delay	5.0	3.0	–	11.5	2.5	13.0	ns	3–6
t _{PHL}	Propagation Delay	5.0	3.0	–	11.0	2.5	12.5	ns	3–5

*Voltage Range 5.0 V is 5.0 V ±0.5 V.

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INPUT CHARACTERISTICS (unless otherwise specified)

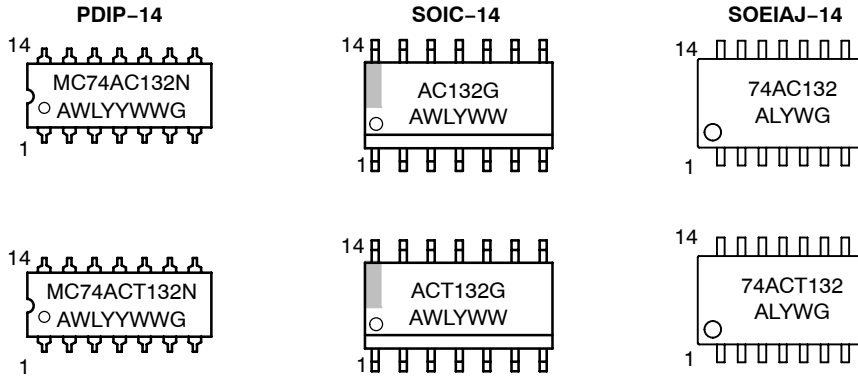
Symbol	Parameter	V _{CC} (V)	74AC	74ACT	Unit	Test Conditions
V _{t+}	Maximum Positive Threshold	3.0	2.2	2.0	V	T _A = Worst Case
		4.5	3.2			
		5.5	3.9			
V _{t-}	Minimum Negative Threshold	3.0	0.5	0.8	V	T _A = Worst Case
		4.5	0.9			
		5.5	1.1			
V _{h(max)}	Maximum Hysteresis	3.0	1.2	1.2	V	T _A = Worst Case
		4.5	1.4			
		5.5	1.6			
V _{h(min)}	Minimum Hysteresis	3.0	0.3	0.4	V	T _A = Worst Case
		4.5	0.4			
		5.5	0.5			

CAPACITANCE

Symbol	Parameter	Value Typ	Unit	Test Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = 5.0 V
C _{PD}	Power Dissipation Capacitance	30	pF	V _{CC} = 5.0 V

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MARKING DIAGRAMS



A = Assembly Location
 WL, L = Wafer Lot
 YY, Y = Year
 WW, W = Work Week
 G = Pb-Free Package

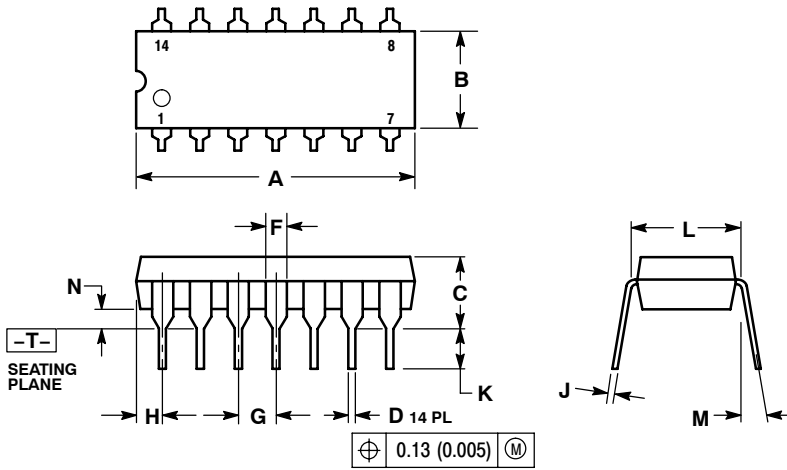
ORDERING INFORMATION

Device	Package	Shipping [†]
MC74AC132N	PDIP-14	25 Units/Rail
MC74AC132NG	PDIP-14 (Pb-Free)	
MC74ACT132N	PDIP-14	
MC74ACT132NG	PDIP-14 (Pb-Free)	
MC74AC132D	SOIC-14	55 Units/Rail
MC74AC132DG	SOIC-14 (Pb-Free)	
MC74AC132DR2	SOIC-14	
MC74AC132DR2G	SOIC-14 (Pb-Free)	2500/Tape & Reel
MC74ACT132D	SOIC-14	55 Units/Rail
MC74ACT132DG	SOIC-14 (Pb-Free)	
MC74ACT132DR2	SOIC-14	2500/Tape & Reel
MC74ACT132DR2G	SOIC-14 (Pb-Free)	
MC74AC132MEL	SOEIAJ-14	2000/Tape & Reel
MC74AC132MELG	SOEIAJ-14 (Pb-Free)	
MC74ACT132MEL	SOEIAJ-14	
MC74ACT132MELG	SOEIAJ-14 (Pb-Free)	

MC74AC132, MC74ACT132

PACKAGE DIMENSIONS

PDIP-14
CASE 646-06
ISSUE P



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
4. DIMENSION B DOES NOT INCLUDE MOLD FLASH.
5. ROUNDED CORNERS OPTIONAL.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.715	0.770	18.16	19.56
B	0.240	0.260	6.10	6.60
C	0.145	0.185	3.69	4.69
D	0.015	0.021	0.38	0.53
F	0.040	0.070	1.02	1.78
G	0.100 BSC		2.54 BSC	
H	0.052	0.095	1.32	2.41
J	0.008	0.015	0.20	0.38
K	0.115	0.135	2.92	3.43
L	0.290	0.310	7.37	7.87
M	---	10°	---	10°
N	0.015	0.039	0.38	1.01

MC74AC132, MC74ACT132

PACKAGE DIMENSIONS

SOIC-14
CASE 751A-03
ISSUE H



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION.
4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
5. DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	8.55	8.75	0.337	0.344
B	3.80	4.00	0.150	0.157
C	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27 BSC		0.050 BSC	
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
M	0°	7°	0°	7°
P	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

SOLDERING FOOTPRINT*



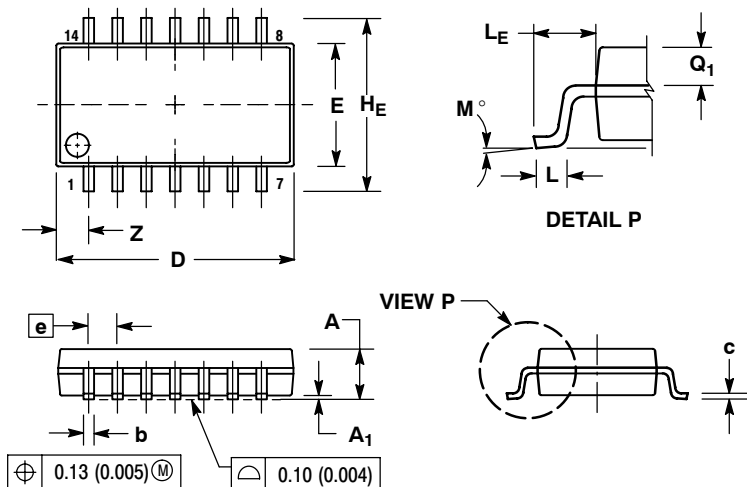
DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

MC74AC132, MC74ACT132

PACKAGE DIMENSIONS

SOEIAJ-14
CASE 965-01
ISSUE A



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: MILLIMETER.
3. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS AND ARE MEASURED AT THE PARTING LINE. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
4. TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
5. THE LEAD WIDTH DIMENSION (b) DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE LEAD WIDTH DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 (0.018).

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	---	2.05	---	0.081
A ₁	0.05	0.20	0.002	0.008
b	0.35	0.50	0.014	0.020
c	0.10	0.20	0.004	0.008
D	9.90	10.50	0.390	0.413
E	5.10	5.45	0.201	0.215
e	1.27 BSC		0.050 BSC	
H _E	7.40	8.20	0.291	0.323
0.50	0.50	0.85	0.020	0.033
L _E	1.10	1.50	0.043	0.059
M	0°	10°	0°	10°
Q ₁	0.70	0.90	0.028	0.035
Z	---	1.42	---	0.056

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